Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/789,339	NUEBEL ET AL.	
Examiner	Art Unit	
TUYEN T. NGUYEN	2832	

	SEAR	CHED	
Class	Subclass	Date	Examiner
336	83, 90-96, 178, 212, 234	1/23/2006	TTN
123	634-635	1/23/2006	TTN

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
		DATE	EXMF
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